Notice of References Cited Application/Control No. 10/711,996 Examiner VAN T. PHAM Applicant(s)/Patent Under Reexamination CHEN ET AL. Art Unit Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0057366	03-2004	Sasaki, Yoshiyuki	369/053.37
*	В	US-7,164,636	01-2007	ljtsma et al.	369/47.53
*	С	US-6,331,966	12-2001	Minami et al.	369/13.07
*	D	US-6,147,943	11-2000	Ogasawara et al.	369/44.32
*	Е	US-6,026,068	02-2000	Obata et al.	369/53.2
*	F	US-5,721,717	02-1998	Obata et al.	369/44.27
*	G	US-6,282,673	08-2001	Liu et al.	714/25
*	H	US-2003/0046599	03-2003	Takamiya et al.	713/600
*	ı	US-2007/0147150	06-2007	Shibuya et al.	365/201
*	J	US-4,855,842	08-1989	Hayes et al.	386/125
*	К	US-6,147,943	11-2000	Ogasawara et al.	369/44.32
	L	US-			
	М	US-			,

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
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NON-PATENT DOCUMENTS

*	·	:	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	x		

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.